

Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from, Europe, America and south Asia, supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



# Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832

Email & Skype: info@chipsmall.com Web: www.chipsmall.com

Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China











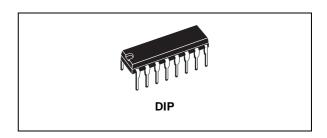
## PROGRAMMABLE TIMER

- 24 FLIP-FLOP STAGES COUNTS FROM 2<sup>0</sup> TO 2<sup>24</sup>
- LAST 16 STAGES SELECTABLE BY BCD SELECT CODE
- GROUP SELECT INDICATES ONE OR MORE PRIORITY INPUTS
- QUIESCENT CURRENT SPECIFIED UP TO 20V
- STANDARDIZED SYMMETRICAL OUTPUT CHARACTERISTICS
- 5V, 10V AND 15V PARAMETRIC RATINGS
- INPUT LEAKAGE CURRENT I<sub>I</sub> = 100nA (MAX) AT V<sub>DD</sub> = 18V T<sub>A</sub> = 25°C
- 100% TESTED FOR QUIESCENT CURRENT
- MEETS ALL REQUIREMENTS OF JEDEC JESD13B "STANDARD SPECIFICATIONS FOR DESCRIPTION OF B SERIES CMOS DEVICES"

## **DESCRIPTION**

HCF4536B is a monolithic integrated circuit fabricated in Metal Oxide Semiconductor technology available in DIP package.

HCF4536B is a programmable timer consisting of 24 ripple-binary counter stages. The salient feature of this device is its flexibility. The device can count from 1 to 2<sup>24</sup> or the first 3 stages can be bypassed to allow an output, selectable by a 4-bit code, from any one of the remaining 16 stages. It

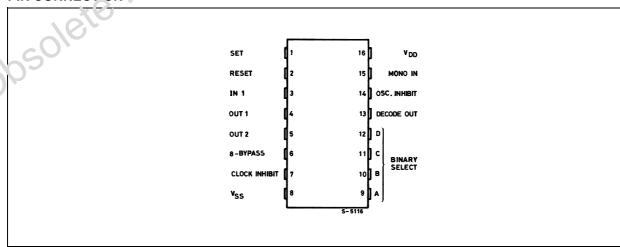


#### **ORDER CODES**

PACKAGE	TUBE	1 & R
DIP	HCF4536BEY	

can be driven by an external clock or an RC oscillator that can be constructed using on-chip components. Input IN1 serves as either the external clock or ut or the input to the on-chip RC oscillator. OUT1 and OUT2 are connection terminals for the external RC components. In addition, an on-chip monostable circuit is provided to allow a variable pulse width output. Various timing functions can be achieved using combinations of these capabilities. A logic "1" on the 8-BYPASS input enables a bypass of the first 8 stages and makes stage 9 the first counter stage of the last 16 stages. Selection of 1 of 16 outputs is accomplished by the decoder and the BCD inputs A, B, C, and D. MONO IN is the timing input

### **PIN CONNECTION**

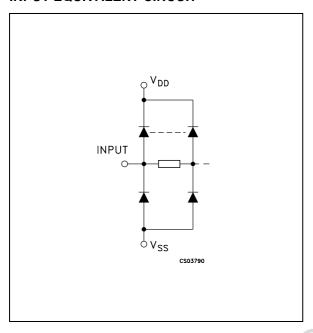


October 2002 1/13

for the on-chip monostable oscillator. Grounding of the MONO IN terminal through a resistor of 10  $\rm K\Omega$  or higher, disables the one shot circuit and connects the decoder directly to the DECODE OUT terminal. A resistor to  $\rm V_{DD}$  and a capacitor to ground from the MONO IN terminal enables the

one-shot circuit and controls its pulse width. A fast test mode is enabled by a logic "1" on 8-BYPASS, SET, and RESET. This mode divides the 24-stage counter into three 8-stage sections to facilitate a fast test sequence.

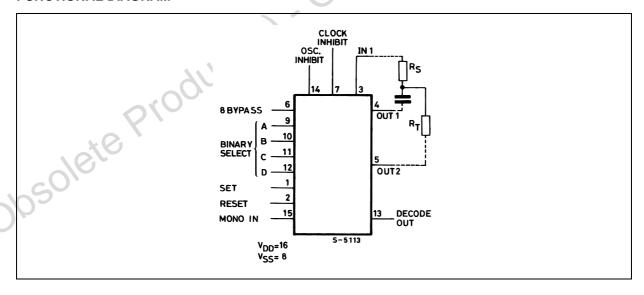
### INPUT EQUIVALENT CIRCUIT



### **PIN DESCRIPTION**

PIN No	SYMBOL	NAME AND FUNCTION		
9, 10, 11, 12	A, B, C, D	Binary Select Input		
1	SET	Set input		
2	RESET	Reset Input		
15	MONO IN	Monostable OscillatorTiming Input		
6	8BYPASS	8Bypass input( bypass the first 8 stages)		
3	IN1	External Clock Input or RC oscillator Input		
4, 5	OUT1, OUT2	Outputs		
13	DECODE OUT	Decode Out Terminal		
7	CLOCK INHIBIT	Clock Inhibit Input		
14	OSC. INHIBIT	Oscillator Inhibit Input		
8	V <sub>SS</sub>	Negative Supply Voltage		
16	$V_{DD}$	Positive Supply Voltage		

### **FUNCTIONAL DIAGRAM**



## **TRUTH TABLE**

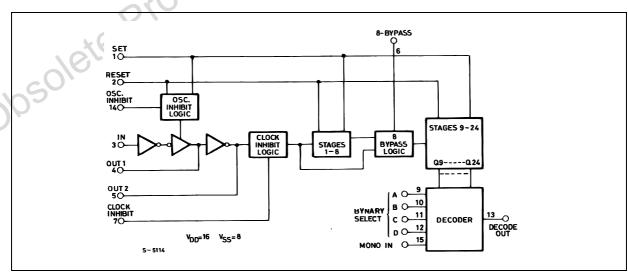
ln1	Set	Reset	Clock Inh	Osc. Inh	Out1	Out2	Decode Out
」	L	L	L	L	7	7	No Change
	L	L	L	L	7_		Advance to Next State
Х	Н	L	L	L	L	Н	Н
Х	L	Н	L	L	L	Н	L
Х	L	L	Н	L			No Change
L	L	L	L	Х	L	Н	No Change
Н	L	L	L	7	7	7	Advance to Next State

X : Don't Care

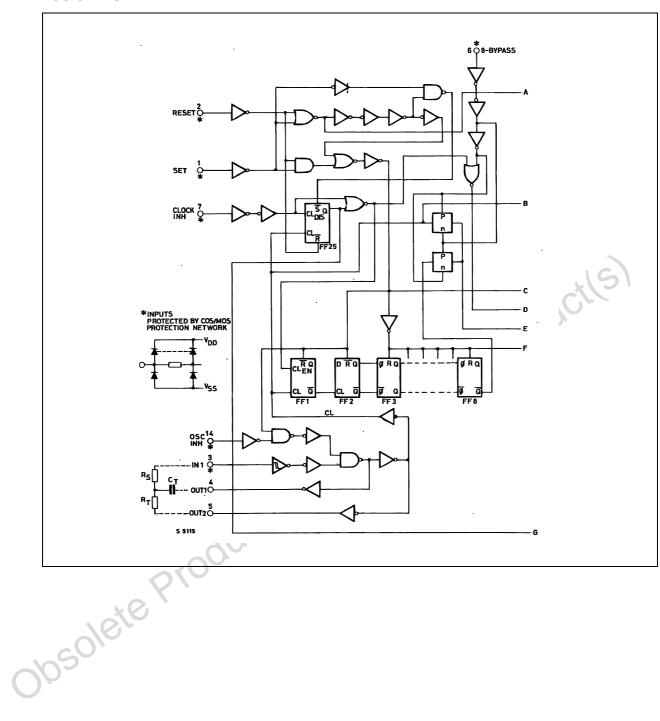
## **DECODE OUT SELECTION TABLE**

<b>D</b>	D C		Δ.	NUMBER OF STAGE	S IN DIVIDER CHAIN
J 0	C	В	Α	8-BYPASS = 0	8-BYPASS = 1
L	L	L	L	9	.151
L	L	L	Н	10	2
L	L	Н	L	11	3
L	L	Н	Н	12	4
L	Н	L	L	13	5
L	Н	L	Н	14	6
L	Н	Н	L	15	7
L	Н	Н	Н	16	8
Н	L	L	L	17	9
Н	L	L	Н	18	10
Н	L	Н	L	19	11
Н	L	Н	Н	20	12
Н	Н	L	/ L	21	13
Н	Н	LIG	Н	22	14
Н	Н	H	L	23	15
Н	Н	Н	Н	24	16

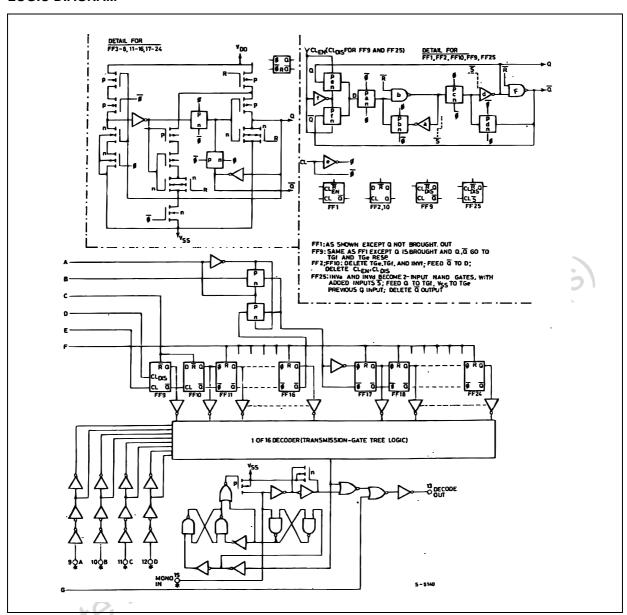
### **BLOCK DIAGRAM**



### **LOGIC DIAGRAM**



### **LOGIC DIAGRAM**



## **ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Value	Unit
$V_{DD}$	Supply Voltage	-0.5 to +22	V
V <sub>I</sub>	DC Input Voltage	-0.5 to V <sub>DD</sub> + 0.5	V
l <sub>l</sub>	DC Input Current	± 10	mA
P <sub>D</sub>	Power Dissipation per Package	200	mW
	Power Dissipation per Output Transistor	100	mW
T <sub>op</sub>	Operating Temperature	-55 to +125	°C
T <sub>stg</sub>	Storage Temperature	-65 to +150	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied. All voltage values are referred to V<sub>SS</sub> pin voltage.



## **RECOMMENDED OPERATING CONDITIONS**

Symbol	Parameter	Value	Unit
V <sub>DD</sub>	Supply Voltage	3 to 20	V
V <sub>I</sub>	Input Voltage	0 to V <sub>DD</sub>	V
T <sub>op</sub>	Operating Temperature	-55 to 125	°C

### **DC SPECIFICATIONS**

			Test Con	dition		Value							
Symbol Parameter		VI	٧o	I <sub>O</sub>	$V_{DD}$	Т	A = 25°	С	-40 to	85°C	-55 to	125°C	Unit
		(V)	(V)	<b>(μA)</b>	(V)	Min.	Тур.	Max.	Min.	Max.	Min.	Max.	
ΙL	Quiescent Current	0/5			5		0.04	5		150		150	
		0/10			10		0.04	10		300		300	^
		0/15			15		0.04	20		600		600	μΑ
		0/20			20		0.08	100		3000		3000	
V <sub>OH</sub>	High Level Output	0/5		<1	5	4.95			4.95		4.95	12	
	Voltage	0/10		<1	10	9.95			9.95		9.95		V
		0/15		<1	15	14.95			14.95	7	14.95		
V <sub>OL</sub>	Low Level Output	5/0		<1	5		0.05			0.05		0.05	
	Voltage	10/0		<1	10		0.05			0.05		0.05	V
		15/0		<1	15		0.05			0.05		0.05	
V <sub>IH</sub>	High Level Input		0.5/4.5	<1	5	3.5		10	3.5		3.5		
	Voltage		1/9	<1	10	7	10		7		7		V
			1.5/13.5	<1	15	11			11		11		
V <sub>IL</sub>	Low Level Input		4.5/0.5	<1	5	C		1.5		1.5		1.5	
	Voltage		9/1	<1	10	10,		3		3		3	V
			13.5/1.5	<1	15	7		4		4		4	
I <sub>OH</sub>	Output Drive	0/5	2.5	<1	5	-1.36	-3.2		-1.1		-1.1		
	Current	0/5	4.6	<1	5	-0.44	-1		-0.36		-0.36		A
		0/10	9.5	<1	10	-1.1	-2.6		-0.9		-0.9		mA
		0/15	13.5	<1	15	-3.0	-6.8		-2.4		-2.4		
I <sub>OL</sub>	L Output Sink	0/5	0.4	<1	5	0.44	1		0.36		0.36		
	Current	0/10	0.5	<1	10	1.1	2.6		0.9		0.9		mΑ
	01	0/15	1.5	<1	15	3.0	6.8		2.4		2.4		
I <sub>I</sub>	Input Leakage Current	0/18	Any In	put	18		±10 <sup>-5</sup>	±0.1		±1		±1	μΑ
Cı	Input Capacitance		Any In	put			5	7.5					pF

The Noise Margin for both "1" and "0" level is: 1V min. with  $V_{DD}$ =5V, 2V min. with  $V_{DD}$ =10V, 2.5V min. with  $V_{DD}$ =15V

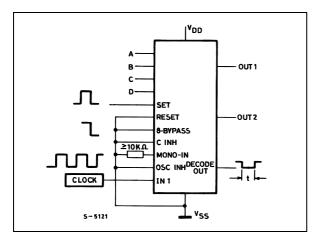
# $\textbf{DYNAMIC ELECTRICAL CHARACTERISTICS} \; (\textbf{T}_{amb} = 25^{\circ} \textbf{C}, \;\; \textbf{C}_{L} = 50 \text{pF}, \; \textbf{R}_{L} = 200 \text{K}\Omega, \;\; \textbf{t}_{f} = \textbf{t}_{f} = 20 \; \text{ns})$

0	<b>D</b> ana 1	Test Condition			Value (*)			
Symbol	Parameter	V <sub>DD</sub> (V)		Min.	Тур.	Max.		
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay Time	5			1	2		
	(Clock to Q1, 8-Bypass	10			0.5	1	μs	
	High)	15			0.35	0.7		
	Propagation Delay Time	5			2.5	5		
	(Clock to Q1, 8-Bypass	10			0.8	0.6	μs	
	Low)	15			0.6	1.2		
	Propagation Delay Time	5			4	8		
	(Clock to Q16)	10			1.5	3	μs	
		15			1	2		
	Propagation Delay Time	5			150	300		
	(Qn to Qn+1)	10			75	150	ns	
		15			50	100		
$t_{PLH}$	Propagation Delay Time	5			300	600		
		10			125	250	ns	
		15			80	160		
$t_{PHL}$	Reset to Qn	5		2	3	6		
		10		0	1	2	μs	
		15			0.75	1.5		
t <sub>THL</sub> t <sub>TLH</sub>	Transition Time	5			100	200		
		10	_*6		50	100	ns	
		15	18		40	80		
$t_W$	Pulse Width Clock	5			200	400		
		10	-103		75	150	ns	
		15			50	100		
	Set	5			200	400		
		10			100	200	ns	
		15			60	120		
	Reset	5			3	6		
	41)	10			1	2	μs	
	200	15			0.75	1.5		
	Recovery Time Set	5			2.5	5		
		10			1	2	μs	
	.0.	15			0.6	1.6		
	Reset	5			3.5	7		
	O	10			1.5	3	μs	
<u>6</u> 0		15			1	2		
t <sub>r,</sub> t <sub>f</sub>	Clock Input Rise or Fall	5						
	Time	10		ι	Jnlimite	d	μs	
		15						
f <sub>CL</sub>	Maximum Clock Input	5		0.5	1			
	Frequency	10		1.5	3		МН	
		15		2.5	5			

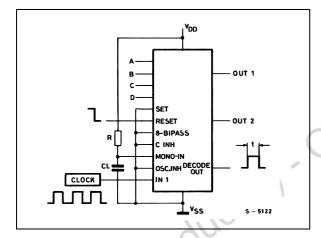
<sup>(\*)</sup> Typical temperature coefficient for all V<sub>DD</sub> value is 0.3 %/°C.

### **TYPICAL APPLICATIONS**

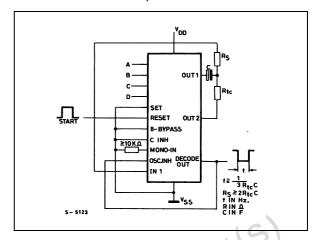
Time Internal Configuration Using External Clock; Set and Clock Inhibit Functions



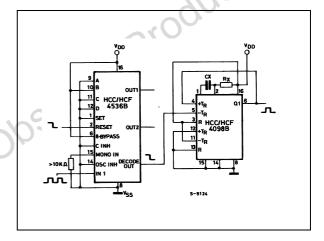
Time Internal Configuration Using Ext. Ck; Reset and Output Monostable to Achieve a Pulse Out



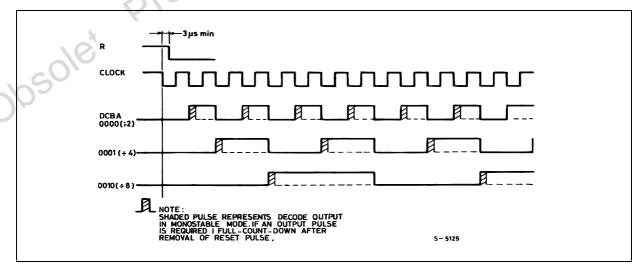
Time Internal Configuration Using On-Chip RC oscillator and Reset Input to Initiate Time Interval



Use of HCF4098B and HCF4536B to get Decode Pulse 8 Clock Pulses after Reset Pulses



### **TIMING DIAGRAM**



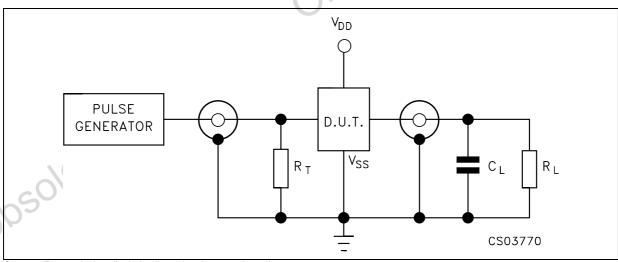
	FUNCTIONAL TEST SEQUENCE										
	Inp	uts		Outputs	COMMENTS						
In 1	Set	Reset	8-Bypass	Decade Out Q1 Thru Q24	All 24 steps are in reset mode						
Н	L	Н	Н	L	Counter is in three 8-stage section in parallel						
Н	Н	Н	Н	L	mode						
L	Н	Н	Н	L	First "H" to "L" Transition of Clock						
Н					255 "H" to "L" transitions are clocked in the						
L	Н	Н	Н		counter						
L	Н	Н	Н	Н	The 255 "H" to "L" Transition						
L	L	L	L	Н	Counter converted back to 24 stages in series mode.  Set and Reset must be connected together and simultaneously go from "H" to "L"						
Н	L	L	L	Н	In <sub>1</sub> switches to a "H"						
L	L	L	L	L	Counter Ripples from an all "H" state to an all "L" state						

### **FUNCTIONAL TEST SEQUENCE**

Test function has been included for the reduction of test time required to exercise all 24 counter stages. This test function divides the counter into three 8-stage section and 255 counts are loaded in each of the 8-stage sections in parallel. All

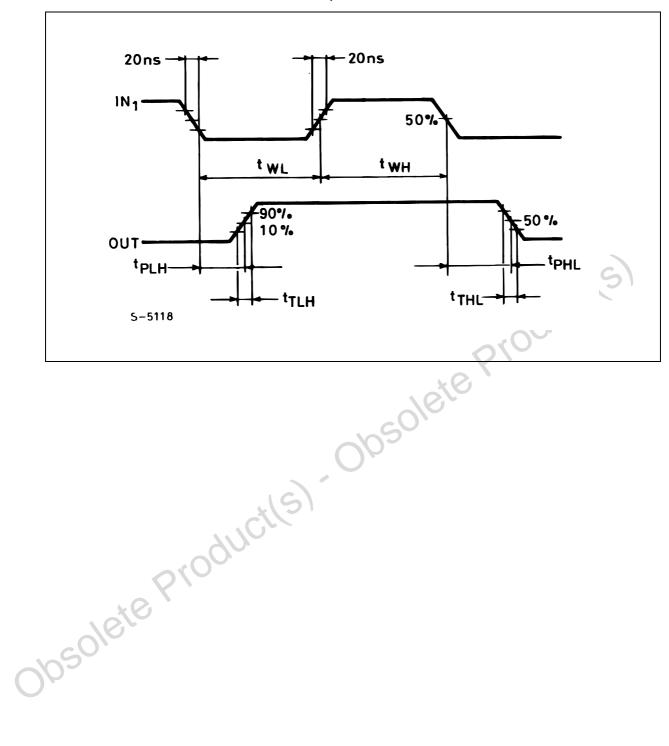
flip-flops are now at a "H". The counter is now returned to the normal 24-steps in series configuration. One more pulse is entered into In1 which will cause the counter to ripple from an all "H" state to an all "L" state.

### **TEST CIRCUIT**



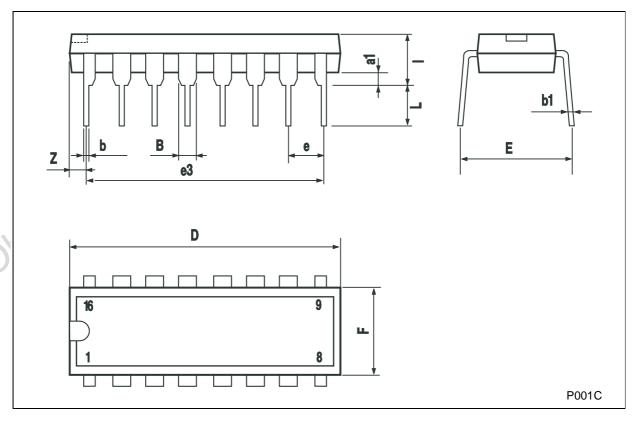
 $C_L$  = 50pF or equivalent (includes jig and probe capacitance)  $R_L$  = 200 $K\Omega$   $R_T$  =  $Z_{OUT}$  of pulse generator (typically 50 $\Omega$ )

## **WAVEFORM: PROPAGATION DELAY TIMES, PULSE WIDTH CLOCK**



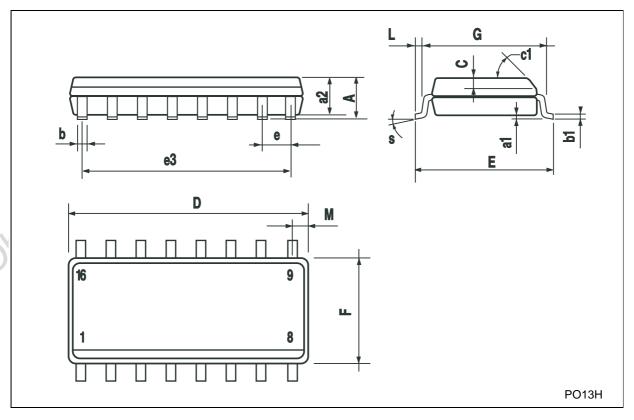
# Plastic DIP-16 (0.25) MECHANICAL DATA

DIM.		mm.		inch				
DIWI.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.		
a1	0.51			0.020				
В	0.77		1.65	0.030		0.065		
b		0.5			0.020			
b1		0.25			0.010			
D			20			0.787		
E		8.5			0.335			
е		2.54			0.100			
e3		17.78			0.700			
F			7.1			0.280		
1			5.1			0.201		
L		3.3			0.130			
Z			1.27			0.050		



# **SO-16 MECHANICAL DATA**

DIM		mm.		inch			
DIM.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.	
Α			1.75			0.068	
a1	0.1		0.2	0.003		0.007	
a2			1.65			0.064	
b	0.35		0.46	0.013		0.018	
b1	0.19		0.25	0.007		0.010	
С		0.5			0.019		
c1			45°	(typ.)			
D	9.8		10	0.385		0.393	
E	5.8		6.2	0.228		0.244	
е		1.27			0.050		
еЗ		8.89			0.350		
F	3.8		4.0	0.149		0.157	
G	4.6		5.3	0.181		0.208	
L	0.5		1.27	0.019		0.050	
М			0.62			0.024	
S			8° (	max.)		•	



Information furnished is believed to be accurate and reliable. However, STMicroelectronics assumes no responsibility for the consequences of use of such information nor for any infringement of patents or other rights of third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of STMicroelectronics. Specifications mentioned in this publication are subject to change without notice. This publication supersedes and replaces all information previously supplied. STMicroelectronics products are not authorized for use as critical components in life support devices or systems without express written approval of STMicroelectronics.

© The ST logo is a registered trademark of STMicroelectronics

© 2002 STMicroelectronics - Printed in Italy - All Rights Reserved STMicroelectronics GROUP OF COMPANIES

Australia - Brazil - Canada - China - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan - Malaysia - Malta - Morocco Singapore - Spain - Sweden - Switzerland - United Kingdom - United States.

© http://www.st.com

